

Search Notes



Application/Control No.

09/925,259

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

ADAMS ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	9/05	DN
	6		
	7		
	8		
	26		
703	1		
	6		
706	46		
	45		
707	6		
	3		
	223	✓	✓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I	US Patent US PG Pub	9/05 DN
II	FOREIGN	
	1. EPO 2. JPO 3. Derwent	✓ ✓
	4. IBM-TDB 5. Derwent	✓ ✓